Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/540,157	TOIDE ET AL.
Examiner	Art Unit
HANH N. NGUYEN	2834

SEARCHED			
Class	Subclass	Date	Examiner
310	216	1/31/2008	HN
310	254	1/31/2008	HN
. H02K	21/00	1/31/2008	HN
H02K	5/18	1/31/2008	HN
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
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